Application/Control No.	Applicant(s)/Patent under Reexamination
09/685,138	LEE, JU-HEON
Examiner	Art Unit
Tanh Q. Nguyen	2182

	SEAR	CHED	
Class	Subclass	Date	Examiner
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INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Consult brian Jhnson on restriction	06/22/06	Tan	